



UNITED STATES PATENT AND TRADEMARK OFFICE

UNITED STATES DEPARTMENT OF COMMERCE
 United States Patent and Trademark Office
 Address: COMMISSIONER FOR PATENTS
 P.O. Box 1450
 Alexandria, Virginia 22313-1450
 www.uspto.gov



Bib Data Sheet

CONFIRMATION NO. 3384

SERIAL NUMBER 10/757,415	FILING OR 371(c) DATE 01/15/2004 RULE	CLASS 703	GROUP ART UNIT 2123	ATTORNEY DOCKET NO. 04173.0441
------------------------------------	---	---------------------	-------------------------------	--

APPLICANTS

Hisashi Kaneko, Fujisawa-shi, JAPAN;
 Motoya Okazaki, Tokyo, JAPAN;
 Hiroyuki Toshima, Saitama-shi, JAPAN;

** CONTINUING DATA *****

None Appl 11/21/06

** FOREIGN APPLICATIONS *****

JAPAN P2003-344526 10/02/2003 *Appl 11/29/06*

IF REQUIRED, FOREIGN FILING LICENSE GRANTED

** 04/19/2004

Foreign Priority claimed <input checked="" type="checkbox"/> yes <input type="checkbox"/> no	STATE OR COUNTRY JAPAN	SHEETS DRAWING 10	TOTAL CLAIMS 22	INDEPENDENT CLAIMS 4
35 USC 119 (a-d) conditions met <input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Met after Allowance Verified and Acknowledged <i>Appl 11/29/06</i> Examiner's Signature Initials				

ADDRESS

22852

TITLE

Simulation circuit pattern evaluation method, manufacturing method of semiconductor integrated circuit, test substrate, and test substrate group

FILING FEE RECEIVED 1022	FEES: Authority has been given in Paper No. _____ to charge/credit DEPOSIT ACCOUNT No. _____ for following:	<input type="checkbox"/> All Fees <input type="checkbox"/> 1.16 Fees (Filing) <input type="checkbox"/> 1.17 Fees (Processing Ext. of time) <input type="checkbox"/> 1.18 Fees (Issue) <input type="checkbox"/> Other _____ <input type="checkbox"/> Credit
------------------------------------	---	---